Appendix 3. Acronyms used to identify different measurement methods

Each acronym has six components, geometry-detector (1)-radiation (1)-detector (2)-radiation (2)-mode. When a component is unknown, ?? is used and when it is not applicable 00 is used.

Geometry	**acronym**	**Detector**	**acronym**
4π	4P	proportional counter	PC
defined solid angle	SA	press. prop counter	PP
2π	2P	liquid scintillation counting	LS
undefined solid angle	UA	NaI(Tl)	NA
		Ge(HP)	GH
		Ge(Li)	GL
		Si(Li)	SL
		CsI(Tl)	CS
		ionization chamber	IC
		grid ionization chamber	GC
		bolometer	BO
		calorimeter	CA
		PIPS detector	PS
Radiation	**acronym**	**Mode**	**acronym**
positron	PO	efficiency tracing	ET
beta particle	BP	internal gas counting	IG
Auger electron	AE	CIEMAT/NIST	CN
conversion electron	CE	sum counting	SC
mixed electrons	ME	coincidence	CO
bremsstrahlung	BS	anti-coincidence	AC
gamma rays	GR	coincidence counting with efficiency tracing	CT
X - rays	XR	anti-coincidence counting with efficiency tracing	AT
photons (x + γ)	PH	triple-to-double coincidence ratio counting	TD
photons + electrons	PE	selective sampling	SS
alpha - particle	AP	high efficiency	HE
mixture of various radiation	MX	digital coincidence counting	DC

Examples **method**	**acronym**
4π(PC)β–γ-coincidence counting	4P-PC-BP-NA-GR-CO
4π(PPC)β–γ-coincidence counting eff. trac.	4P-PP-MX-NA-GR-CT
defined solid angle α-particle counting with a PIPS detector	SA-PS-AP-00-00-00
4π(PPC)AX-γ(GeHP)-anticoincidence counting	4P-PP-MX-GH-GR-AC
4π CsI-β,AX,γ counting	4P-CS-MX-00-00-HE
calibrated IC	4P-IC-GR-00-00-00
internal gas counting	4P-PC-BP-00-00-IG